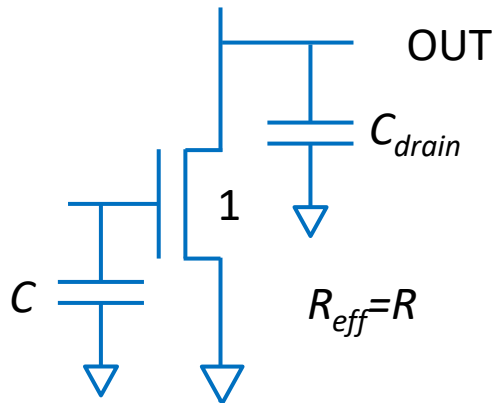


# Q & A session

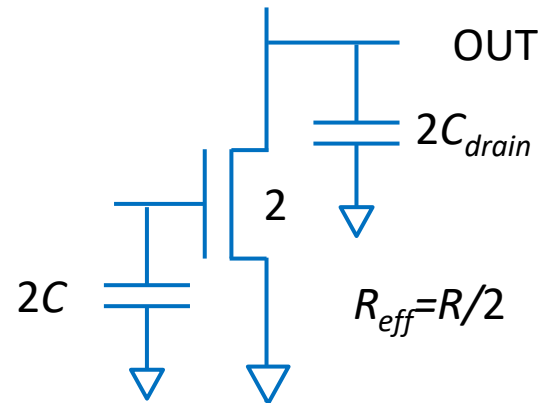
Lecture 5

# Transistor sizing

If these are the  $R$  and  $C$  parameters of the unit width n-channel MOSFET . . .



. . . what would be the  $R$  and  $C$  parameters of a 2 unit width n-channel MOSFET?



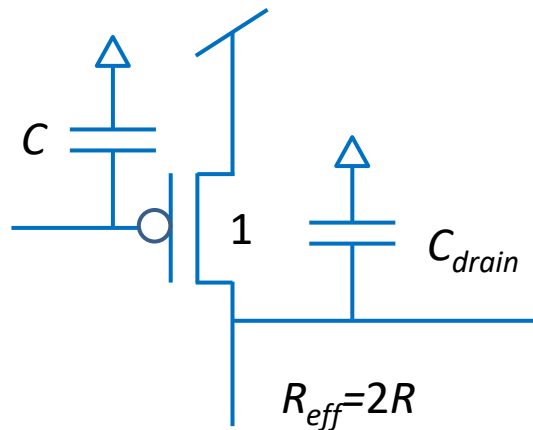
The unit width is just arbitrarily chosen, but for any width  $W$ , the MOSFET gate capacitance and its effective resistance can be calculated as shown below

$$R_{eff} = \frac{2}{W} \frac{[\text{k}\Omega \times \mu\text{m}]}{[\mu\text{m}]}, \quad C_{gate} = 1.2 \times W \text{ [fF}/\mu\text{m}] \times [\mu\text{m}], \quad C_{drain} = p_{inv} C_{gate}$$

# CMOS inverter – Transistor sizing

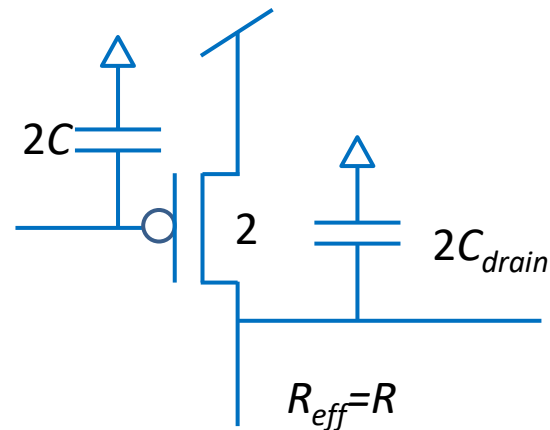
Q: What if the MOSFET is a p-channel device?

The  $R$  and  $C$  parameters of the unit width p-channel MOSFET



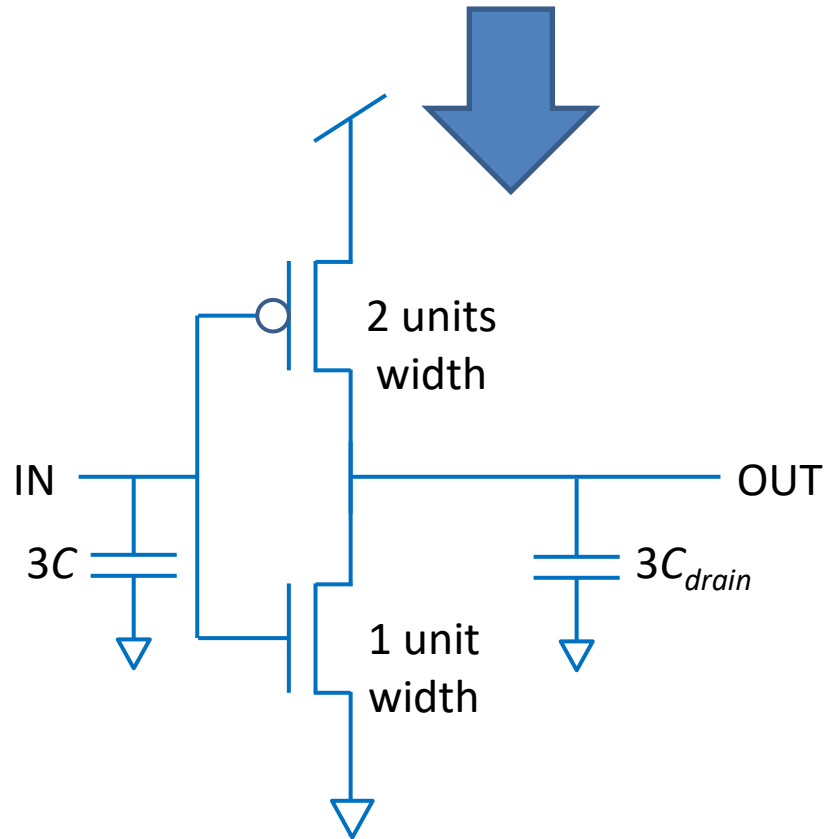
The higher effective resistance is because of the hole mobility in the p-channel being only half of that of the electron mobility in the n-channel.

The  $R$  and  $C$  parameters of the 2 unit width p-channel MOSFET



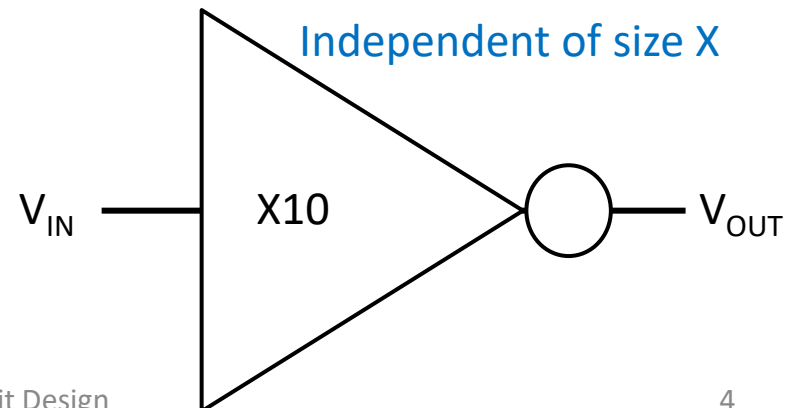
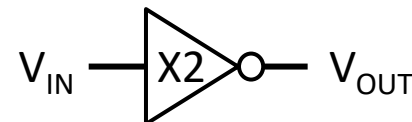
The 2 unit width p-channel device has the same effective resistance as the 1 unit width n-channel device, but twice its capacitances.

# So, this is our reference CMOS inverter



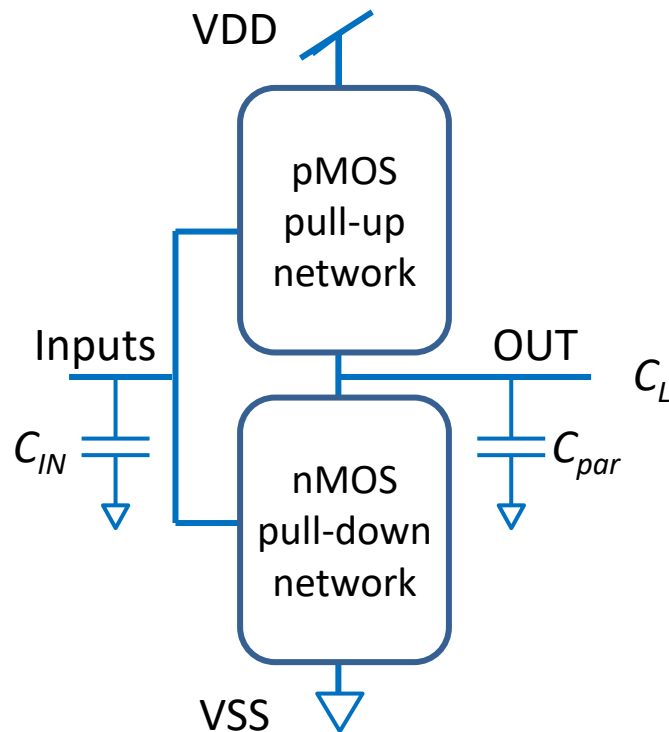
| Size X | WN [nm] | WP [nm] |
|--------|---------|---------|
| 2      | 200     | 400     |
| 3      | 280     | 560     |
| 4      | 370     | 740     |
| 5      | 510     | 1020    |
| 8      | 720     | 1440    |
| 10     | 1000    | 2000    |

All inverters in cell library  
have  $WP/WN=2$



# How to size MOSFETs in a logic gate

Now we want to apply the same model to any CMOS logic gate



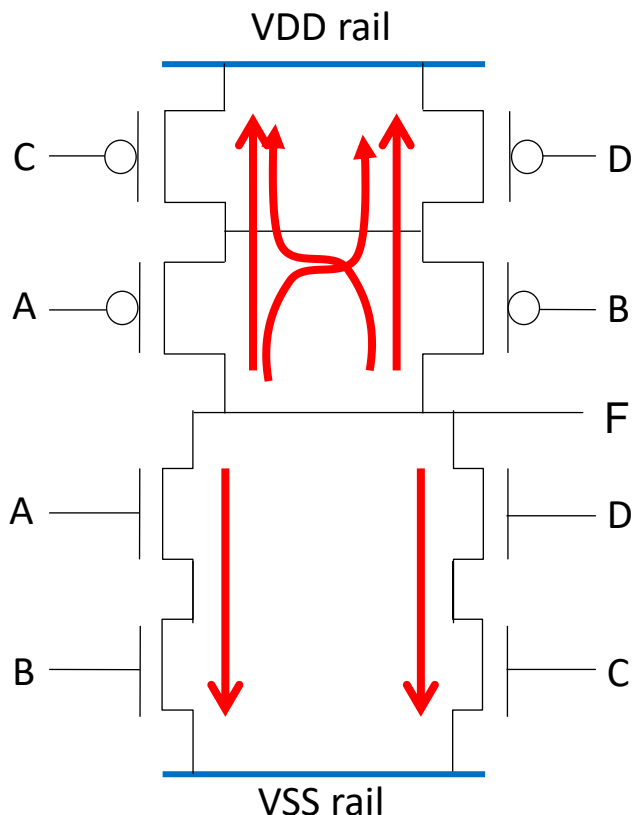
In a logic gate, the pull-up and pull-down networks may have many different resistive paths from the output to the VDD and VSS rails, respectively.

Q: Why do we want all resistive paths to have the same effective resistance?

A: Because it makes life simpler! Just one number to keep track of.

Let the EDA tools keep track of more detailed approaches!

# A logic gate example: the AOI22 gate



The AOI22 gate has two pull-down paths to VSS and four pull-up paths to VDD.

The **worst case** propagation delay occurs when only **one** path connects the output to a rail.

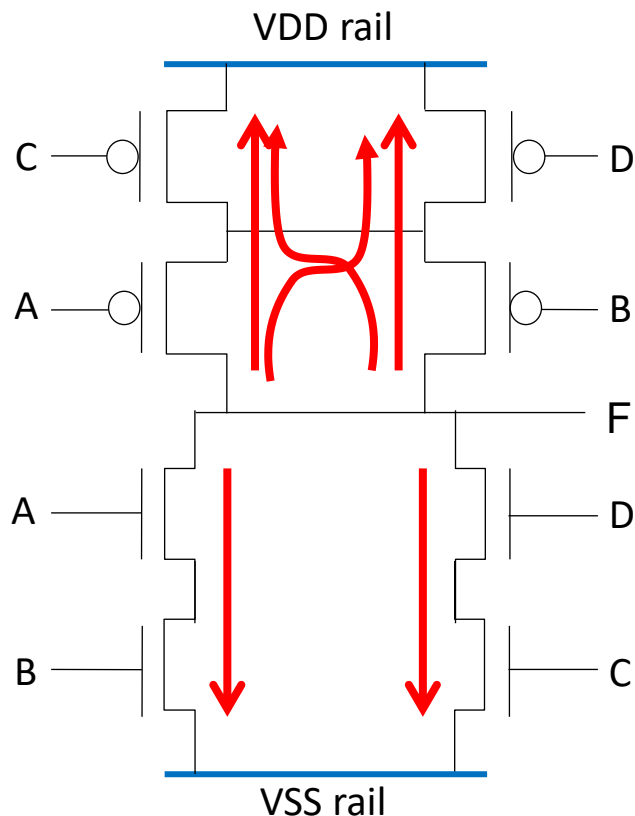
When two or more paths are ON, charging/discharging the load capacitor through parallel paths will be faster.

These cases will not be the speed limiting cases potentially violating the timing constraints.

Q: Which input combinations lead to more than one conducting path?

A: This can be deduced from the Boolean truth table. Obviously  $A=B=C=D=1$  opens up 2 paths to ground. 3 or 4 zero inputs will open up two or more conducting paths to VDD.

# A logic gate example: the AOI22 gate



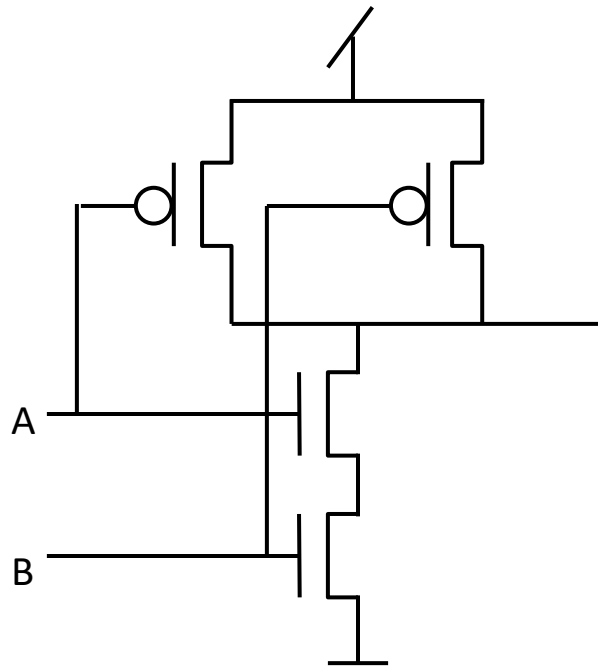
| A | B | C | D | OUT | # ON paths |
|---|---|---|---|-----|------------|
| 0 | 0 | 0 | 0 | 1   | 4↑         |
| 0 | 0 | 0 | 1 | 1   | 2↑         |
| 0 | 0 | 1 | 0 | 1   | 2↑         |
| 0 | 0 | 1 | 1 | 0   | 1↓         |
| 0 | 1 | 0 | 0 | 1   | 2↑         |
| 0 | 1 | 0 | 1 | 1   | 1↑         |
| 0 | 1 | 1 | 0 | 1   | 1↑         |
| 0 | 1 | 1 | 1 | 0   | 1↓         |
| 1 | 0 | 0 | 0 | 1   | 2↑         |
| 1 | 0 | 0 | 1 | 1   | 1↑         |
| 1 | 0 | 1 | 0 | 1   | 1↑         |
| 1 | 0 | 1 | 1 | 0   | 1↓         |
| 1 | 1 | 0 | 0 | 0   | 1↓         |
| 1 | 1 | 0 | 1 | 0   | 1↓         |
| 1 | 1 | 1 | 0 | 0   | 1↓         |
| 1 | 1 | 1 | 1 | 0   | 2↓         |

Q: Which input combinations lead to more than one conducting path?

A: This can be deduced from the Boolean truth table. Obviously  $A=B=C=D=1$  leads to 2 paths to ground. 3 or 4 zero inputs lead to 2 or more conducting paths to VDD.

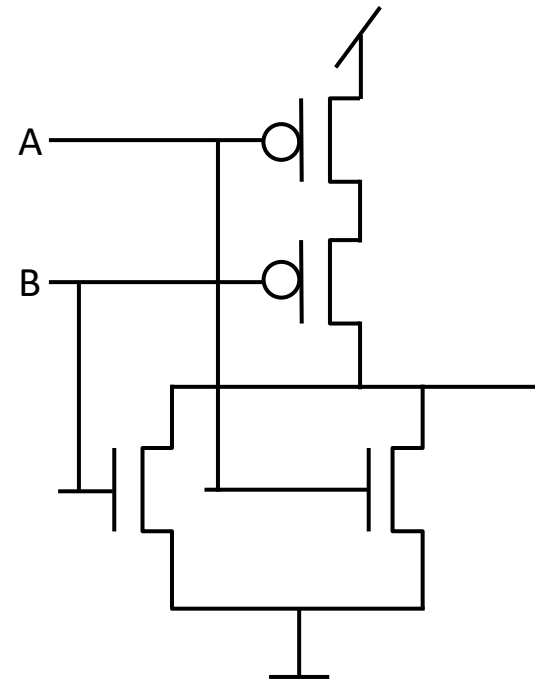
# Exercise:

## Calculate NAND2 NOR2 logical efforts



NAND2

Show that  $g=4/3$ , and  $p=2p_{inv}$



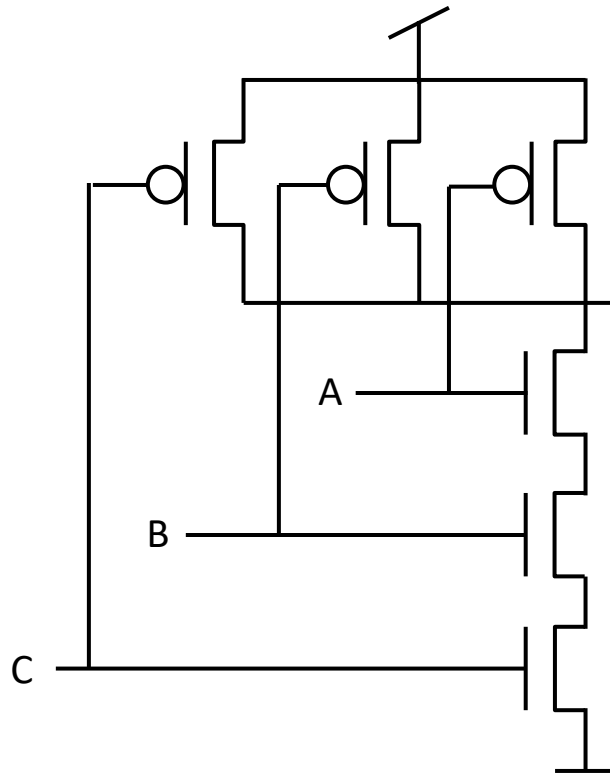
NOR2

Show that  $g=5/3$ , and  $p=2p_{inv}$



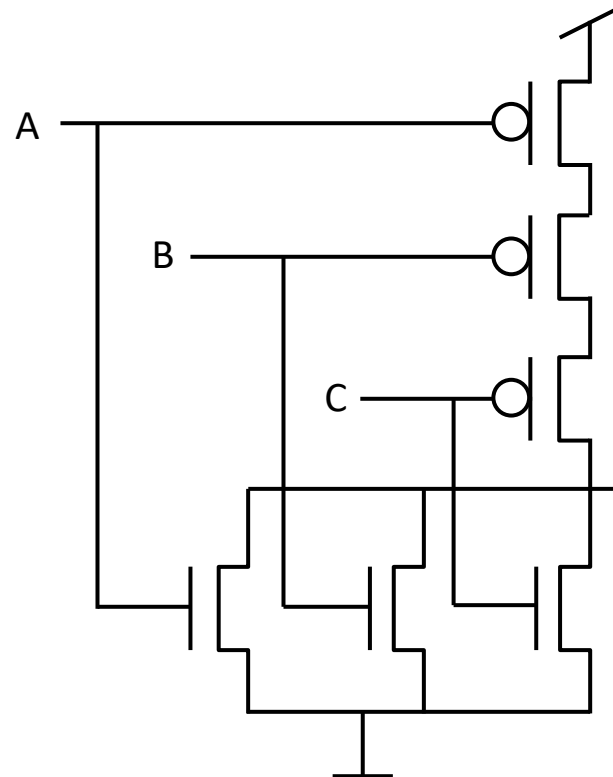
# Exercise:

## Calculate NAND3 & NOR3 logical efforts



NAND3

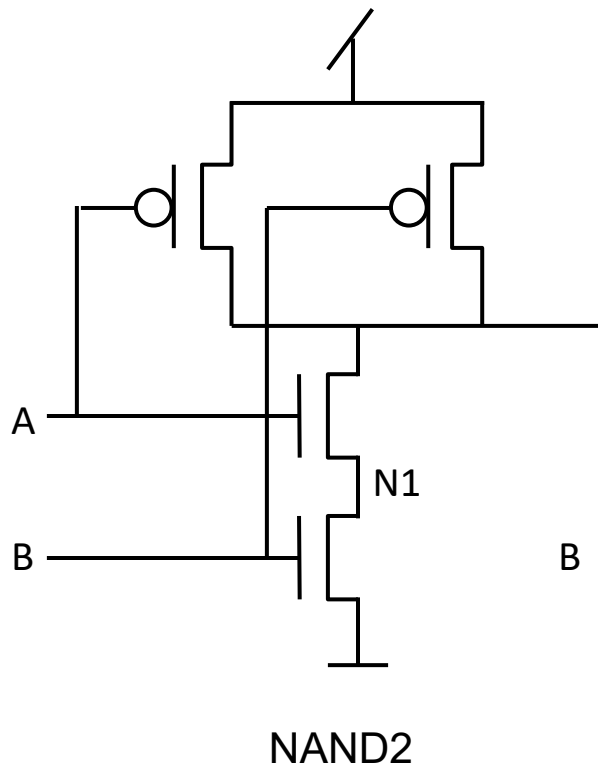
Show that  $g=5/3$ , and  $p=3p_{inv}$



NOR3

Show that  $g=7/3$ , and  $p=3p_{inv}$

# Consider the NAND2 logical gate



Q: Does it make any difference to the switching properties of the NAND2 gate that the source of the A-input n-channel device is not connected to ground?

A: Interesting question. Actually it does. Consider the case when  $A=1$  and  $B=0$ . Both the output and N1 nodes are then at VDD.

The node N1 voltage not being at GND actually increases the threshold voltage of the A-input n-channel device, thereby increasing its effective resistance and making it a bottleneck device once B goes high.

Therefore it is better to arrange inputs so that the B-input goes high before the A input.

When  $A=0$  and  $B=1$ , the N1 node is being discharged to GND. Thereby the threshold voltage of the A-input MOSFET is not affected. Furthermore, node N1 is already discharged when the A-input goes high!

# VT modulation

- The effect that the MOSFET source potential not being at GND affects the threshold voltage is called VT-modulation.
- Why do I tell you about this?
- Because it is going to be important in your carry cell design!
- When you add two bits, a and b, considering an incoming carry from less significant bits, which is the order of signal arrival? Should be considered while designing your cell for the course lab series!

- Design task:

